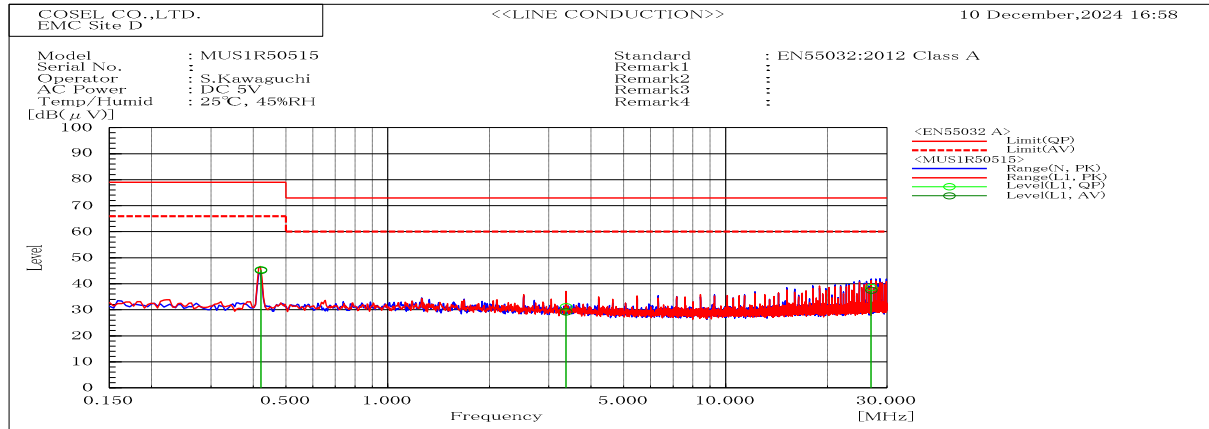
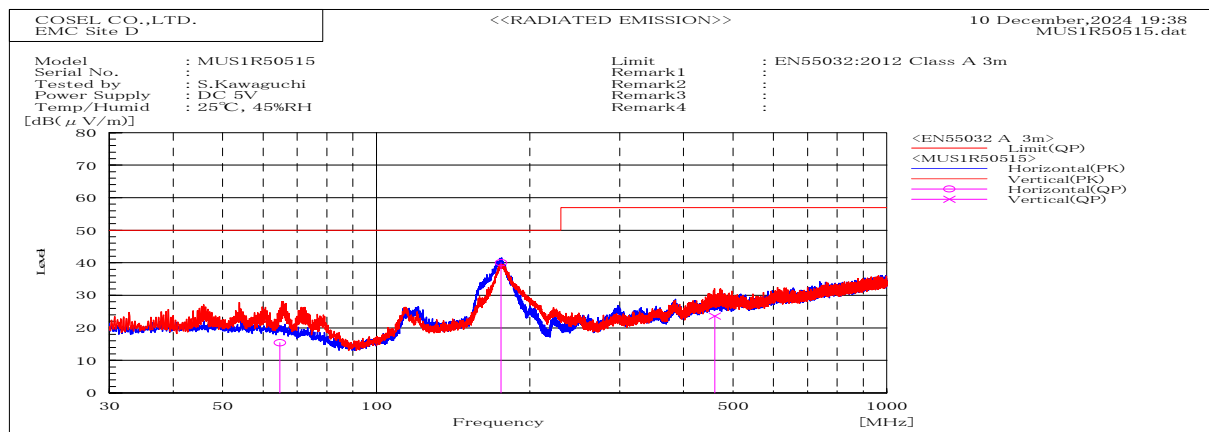


## DATA SHEET

Model		MUS1R50515	Date	05-Mar-25
Test		EMI Line conduction & Radiated emission	Temp.	25 degreeC
			Humid.	45 %RH
			Tested by	S.Kawaguchi



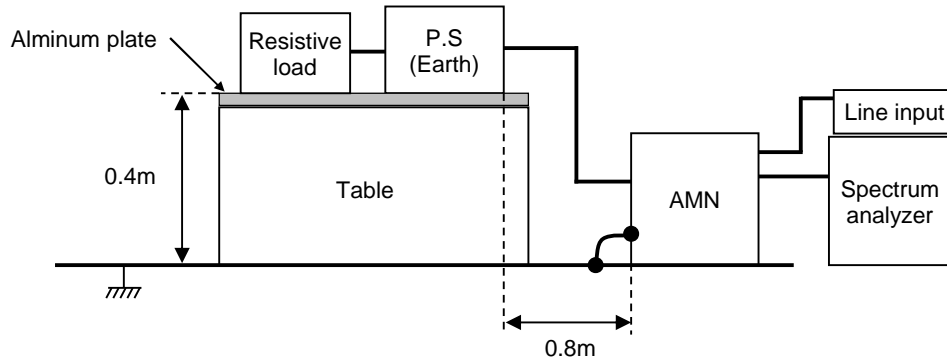
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.421	L1	45.4	45.2	79	66	33.6	20.8	Pass	
3.373	L1	31.1	29.2	73	60	41.9	30.8	Pass	
26.983	L1	38.5	37.5	73	60	34.5	22.5	Pass	



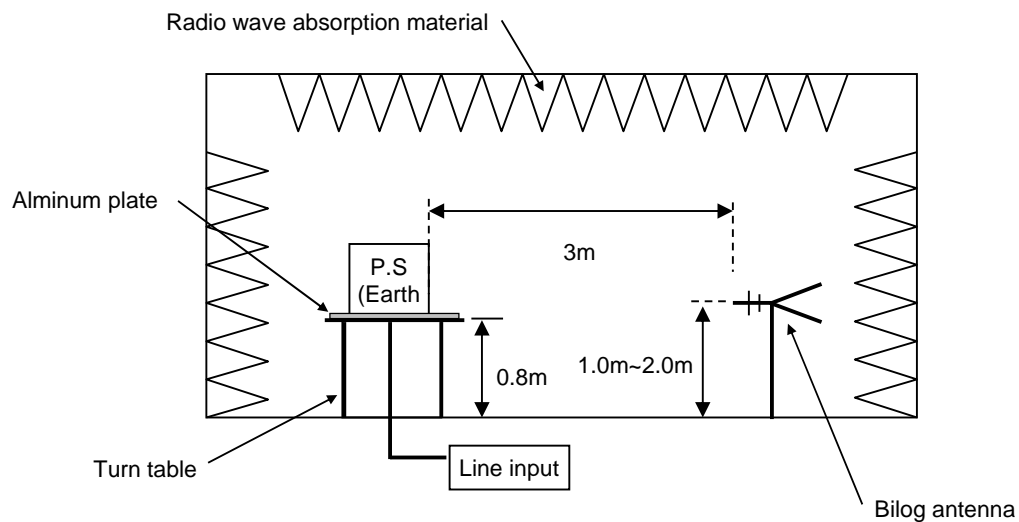
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
175.389	H	Stable	40	50	10	Pass	199.7	229.1	
64.737	H	Stable	15.4	50	34.6	Pass	100	280.7	
460.459	V	Stable	23.6	57	33.4	Pass	116.2	320.3	

DATA SHEET		Date	05-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

### 1. Line conduction



### 2. Radiated emission



## Conditions

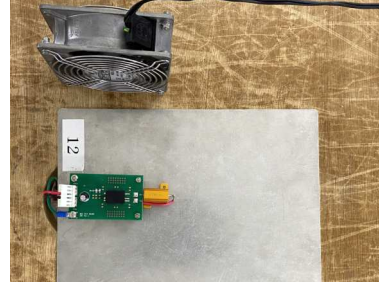
Test : EMI  
Model Name: MUS1R5□□

## ○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



## ○Testing circuitry

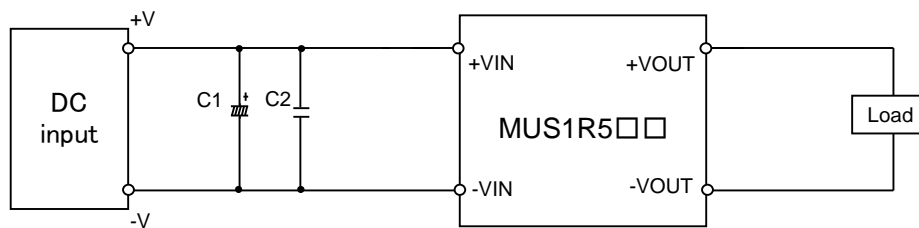


Fig.1 MUS1R505□, MUS1R512□, MUS1R524□ Testing circuitry

C1 :	MUS1R505□	16V 220 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS1R512□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS1R524□	-	
C2 :	MUS1R505□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS1R512□	25V 22 $\mu$ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUS1R524□	50V 10 $\mu$ F	Ceramic capacitor (C3216X7R1H106KT TDK)

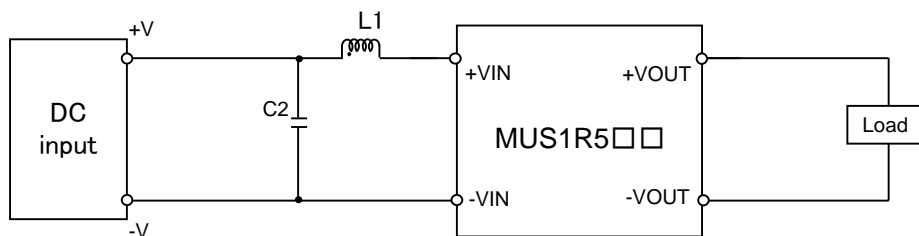


Fig.2 MUS1R548□ Testing circuitry

C2 :	MUS1R548□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS1R548□	520mA 15 $\mu$ H	Inductor (LQH32PN150MN0L MURATA MANUFACTURING)